

<b>Notice of References Cited</b>	Application/Control No. 09/878,554	Applicant(s)/Patent Under Reexamination CHEN ET AL.	
	Examiner Joseph D. Torres	Art Unit 2133	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,242,751 A	12-1980	Henckels et al.	714/737
*	B	US-4,709,366 A	11-1987	Scott et al.	714/46
*	C	US-5,341,314 A	08-1994	Bencivenga et al.	716/4
*	D	US-5,377,201 A	12-1994	Chakradhar et al.	714/741
*	E	US-6,618,826 B1	09-2003	Chen et al.	714/718
*	F	US-5,958,077 A	09-1999	Banerjee et al.	714/738
*	G	US-6,044,214 A	03-2000	Kimura et al.	703/15
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Song, O.; Menon, P.R.; Parallel pattern fault simulation based on stem faults in combinational circuits, Proceedings International Test Conference; 10-14 Sept. 1990, Pages:706 - 711
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.